

Description

The DMP3021SFVWQ-13 uses advanced trench technology to provide excellent $R_{DS(ON)}$, low gate charge and operation with gate voltages as low as 4.5V. This device is suitable for use as a Battery protection or in other Switching application.

General Features

 $V_{DS} = -30V I_{D} = -50 A$

 $R_{DS(ON)}$ < 13m Ω @ V_{GS} =-10V

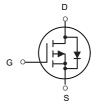
Application

Battery protection

Load switch

Uninterruptible power supply





P-Channel MOSFET

Package Marking and Ordering Information

Product ID	Pack	Brand	Qty(PCS)
DMP3021SFVWQ-13	DFN3X3-8L(Power-33-8)	HXY MOSFET	5000

Absolute Maximum Ratings (Tc=25°C unless otherwise specified)

		Rating		Units	
Symbol	Parameter	10s	Steady State	Units	
VDS	Drain-Source Voltage	-30		V	
VGS	Gate-Source Voltage	±20		V	
I _D @T _C =25°C	Continuous Drain Current, V _{GS} @ -10V ¹	-50		Α	
I _D @T _C =100°C	Continuous Drain Current, V _{GS} @ -10V ¹	-27		Α	
I _D @T _A =25°C	Continuous Drain Current, V _{GS} @ -10V ¹	-14.3	-9	Α	
I _D @T _A =70°C	Continuous Drain Current, V _{GS} @ -10V ¹	-11.4	-7.2	Α	
IDM	Pulsed Drain Current ²	-130		Α	
EAS	Single Pulse Avalanche Energy ³	125		mJ	
IAS	Avalanche Current	-50		Α	
P _D @T _C =25°C	Total Power Dissipation ⁴	37		W	
P _D @T _A =25°C	Total Power Dissipation ⁴	4.2	1.67	W	
TSTG	Storage Temperature Range	-55 to 150		°C	
TJ	Operating Junction Temperature Range	-55 to 150		°C	

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R₀JA	Thermal Resistance Junction-Ambient ¹	75	°C/W
R _θ JA	Thermal Resistance Junction-Ambient ¹ (t ≤10s)	30	°C/W
ReJC	Thermal Resistance Junction-Case ¹	3.36	°C/W

Electrical Characteristics (T_J=25°C, unless otherwise noted)

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
BVDSS	Drain-Source Breakdown Voltage	V _{GS} =0V , I _D =-250uA	-30			V
∆BVdss/∆TJ	BVDSS Temperature Coefficient	Reference to 25°C , I _D =-1mA		-0.0232		V/°C
D	Static Drain-Source On-Resistance ²	V _{GS} =-10V , I _D =-30A		9	13	mΩ
Rds(on)		V _{GS} =-4.5V , I _D =-15A		16	22	
V _{GS(th)}	Gate Threshold Voltage		-1.2		-2.5	V
$\triangle V_{GS(th)}$	V _{GS(th)} Temperature Coefficient	V _{GS} =V _{DS} , I _D =-250uA		4.6		mV/°C
		V _{DS} =-24V , V _{GS} =0V , T _J =25°C			-1	uA
IDSS	Drain-Source Leakage Current	V _{DS} =-24V , V _{GS} =0V , T _J =55°C			-5	
Igss	Gate-Source Leakage Current	V _{GS} =±20V , V _{DS} =0V			±100	nA
gfs	Forward Transconductance	V _{DS} =-5V , I _D =-30A		30		S
Rg	Gate Resistance	V _{DS} =0V , V _{GS} =0V , f=1MHz		9		Ω
Qg	Total Gate Charge (-4.5V)			22		
Qgs	Gate-Source Charge	V _{DS} =-15V , V _{GS} =-4.5V , _I _D =-15A		8.7		nC
Qgd	Gate-Drain Charge			7.2		
Td(on)	Turn-On Delay Time			8		
Tr	Rise Time	V _{DD} =-15V , V _{GS} =-10V ,		73.7		
T _{d(off)}	Turn-Off Delay Time	$-R_G=3.3\Omega$		61.8		ns
Tf	Fall Time	I _D =-15A		24.4		
Ciss	Input Capacitance			2215		
Coss	Output Capacitance	V _{DS} =-15V , V _{GS} =0V , f=1MHz		310		pF
Crss	Reverse Transfer Capacitance			237		
ls	Continuous Source Current ^{1,5}	V _G =V _D =0V , Force Current			-42	Α
Іѕм	Pulsed Source Current ^{2,5}				-130	Α
VsD	Diode Forward Voltage ²	V _{GS} =0V , I _S =-1A , T _J =25°C			-1	V
t _{rr}	Reverse Recovery Time	IF=-15A , dI/dt=100A/μs ,		19		nS
Q _{rr}	Reverse Recovery Charge	T _J =25°C		9		nC

Note:

- 1.The data tested by surface mounted on a 1 inch² FR-4 board with 2OZ copper.
- 2.The data tested by pulsed , pulse width $\leq 300 \text{us} \;\; \text{duty cycle} \leq \!\! 2\%$
- 3.The EAS data shows Max. rating . The test condition is V_{DD} =-25V V_{GS} =-10V,L=0.1mH,IAS=-50A,
- 4.The power dissipation is limited by 150°C junction temperature
- 5.The data is theoretically the same as ID and IDM, in real applications, should be limited by total power dissipation.



Typical Characteristics

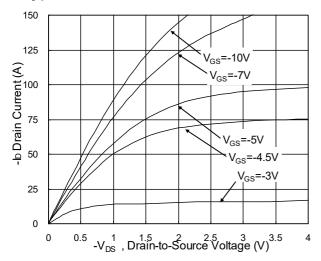


Fig.1 Typical Output Characteristics

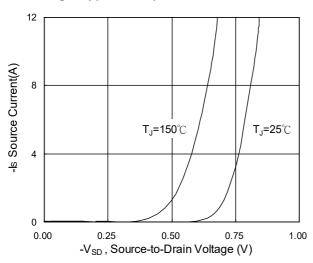


Fig.3 Forward Characteristics of Reverse

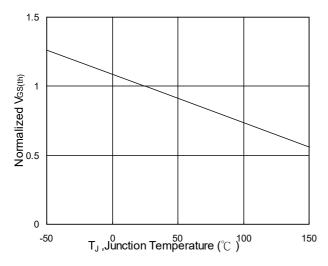


Fig.5 Normalized V_{GS(th)} vs. T_J

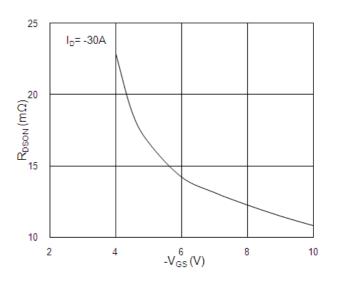


Fig.2 On-Resistance vs. G-S Voltage

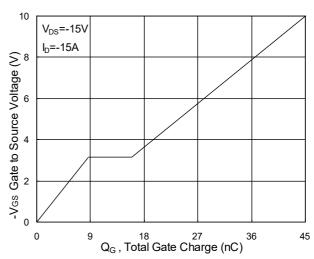


Fig.4 Gate-Charge Characteristics

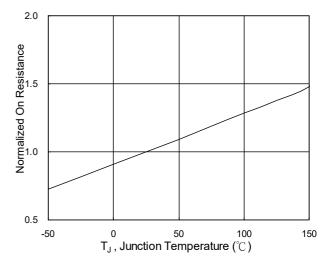
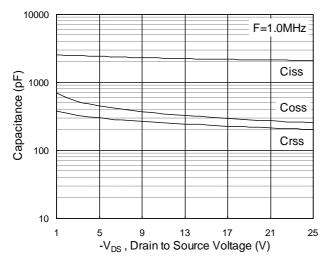


Fig.6 Normalized R_{DSON} vs. T_J





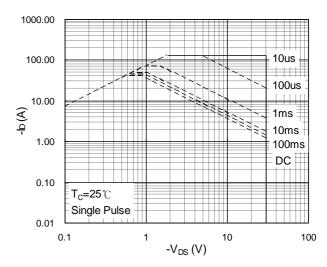


Fig.7 Capacitance

Fig.8 Safe Operating Area

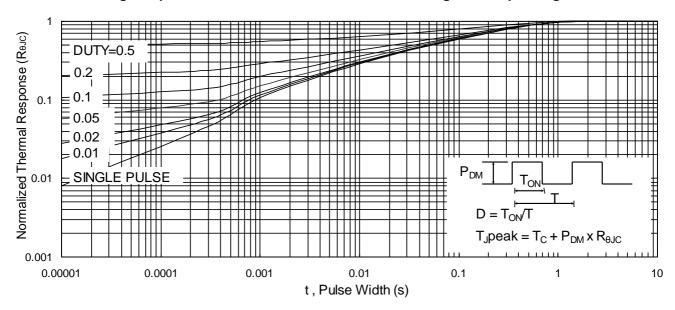


Fig.9 Normalized Maximum Transient Thermal Impedance

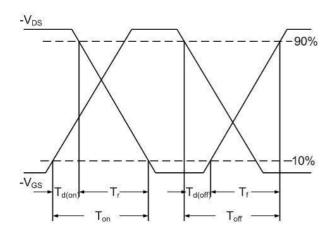


Fig.10 Switching Time Waveform

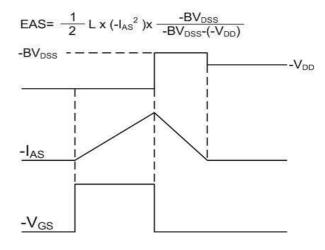
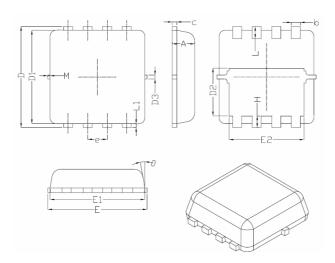


Fig.11 Unclamped Inductive Switching Waveform



DFN3X3-8L(Power-33-8) Package Information



Complete I	Dimensions In Millimeters			
Symbol	Min.	Nom.	Max.	
A	0.70	0.75	0.80	
b	0.25	0.30	0.35	
С	0.10	0.15	0.25	
D	3.25	3.35	3.45	
D1	3.00	3.10	3.20	
D2	1.48	1.58	1.68	
D3	-	0.13	-	
E	3.20	3.30	3.40	
E1	3.00	3.15	3.20	
E2	2.39	2.49	2.59	
е	0.65BSC			
Н	0.30	0.39	0.50	
L	0.30	0.40	0.50	
L1	-	0.13	-	
M	*	*	0.15	
θ		10 [°]	12 [°]	

P-Channel Enhancement Mode MOSFET

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